

**A fault-resistant architecture for AES S-box architecture**

**Taheri, Mahdi**; Sheikhpour, Saeideh; Ansari, Mohammad Saeed; Mahani, Ali Journal of Applied Research in Electrical Engineering 2021 / p. 86-92 <https://doi.org/10.22055/jaree.2021.36230.1020>

**A high-performance MEMRISTOR-based Smith-Waterman DNA sequence alignment using FPN structure**

**Taheri, Mahdi**; Zandevakili, Hamed; Mahani, Ali Journal of Applied Research in Electrical Engineering 2021 / p. 59-68  
<https://doi.org/10.22055/jaree.2021.36117.1016>

**A novel fault-tolerant logic style with self-checking capability**

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